

Passivated Porous Silicon Membranes and their Application to Optical Biosensing

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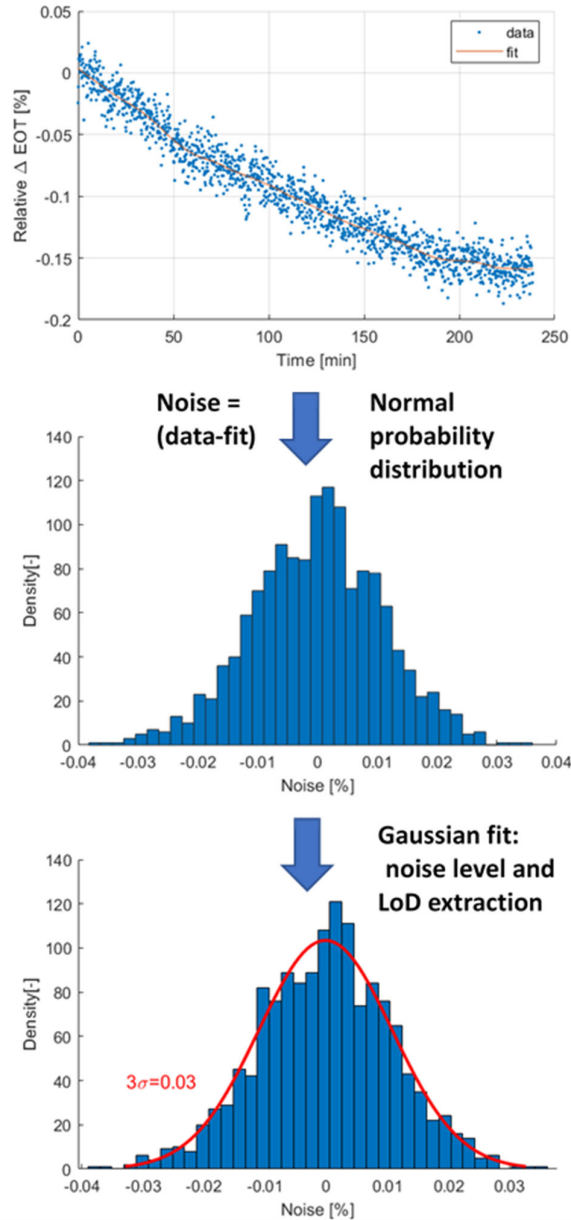


Figure S1. Schematic representation of the noise level analysis procedure: (1) the data is fit using a moving average (low pass filter with coefficient equal to the reciprocal of the span, span=0.15), (2) the noise is calculated by taking the difference between the data and the fit, (3) a normal probability distribution is plotted from the calculated noise, (4) a Gaussian fit is applied to the distribution, allowing to extract the noise level σ_N .

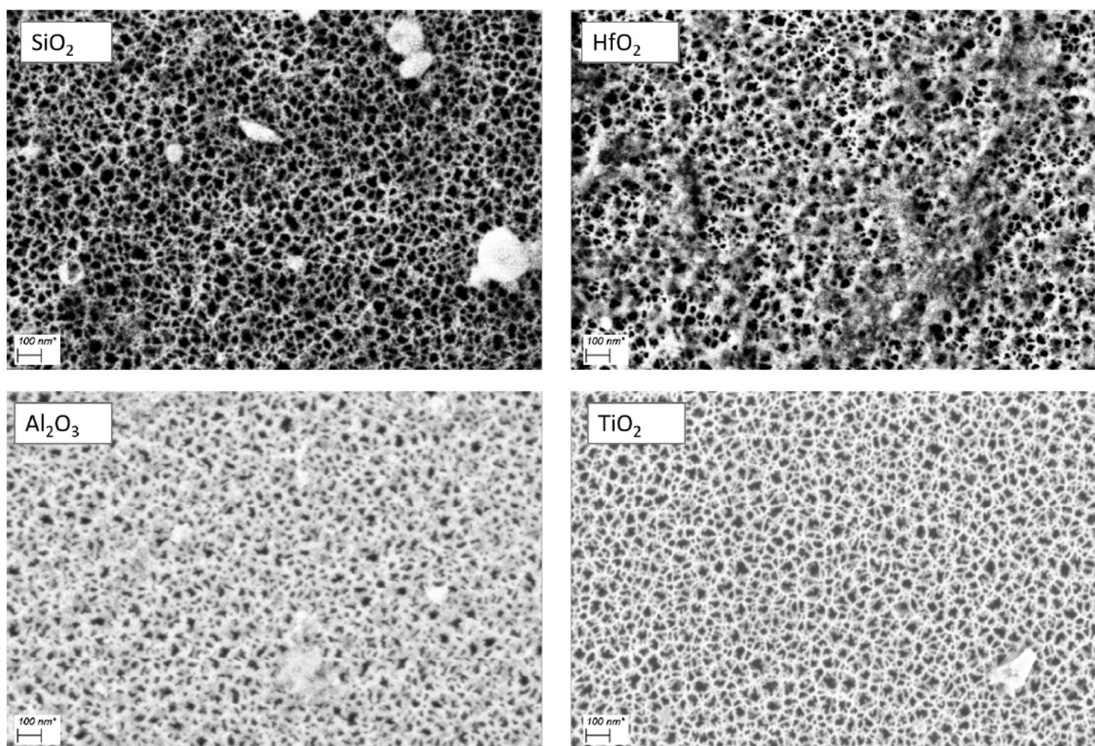


Figure S2. SEM images of the surface of porous silicon membranes: PSiO₂, PSiO₂/HfO₂, PSiO₂/Al₂O₃ and PSiO₂/TiO₂.

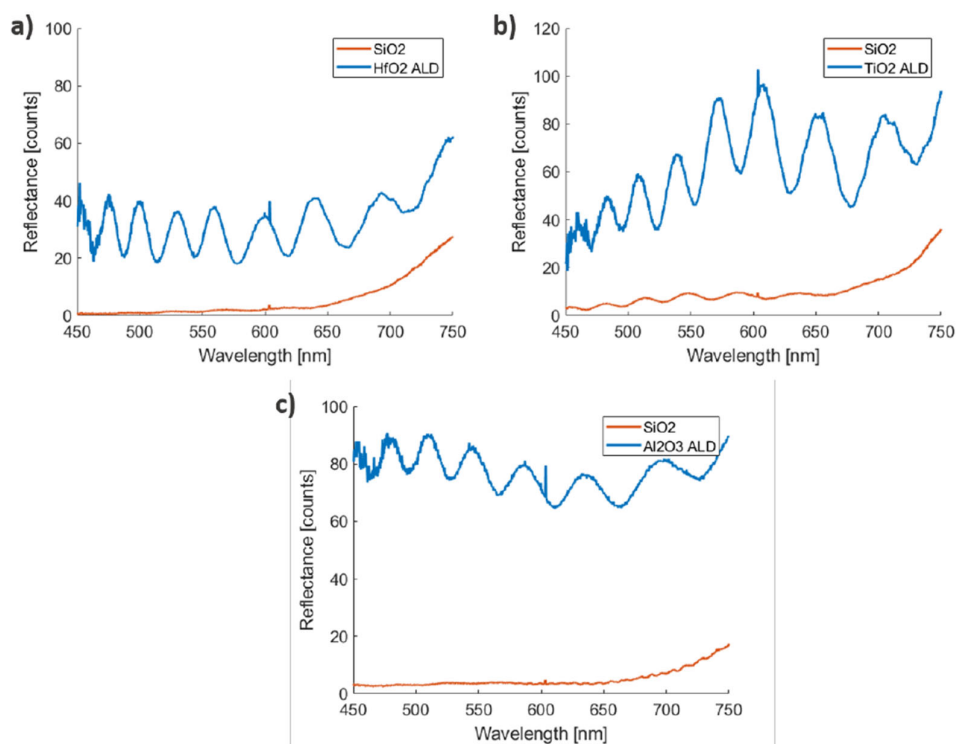
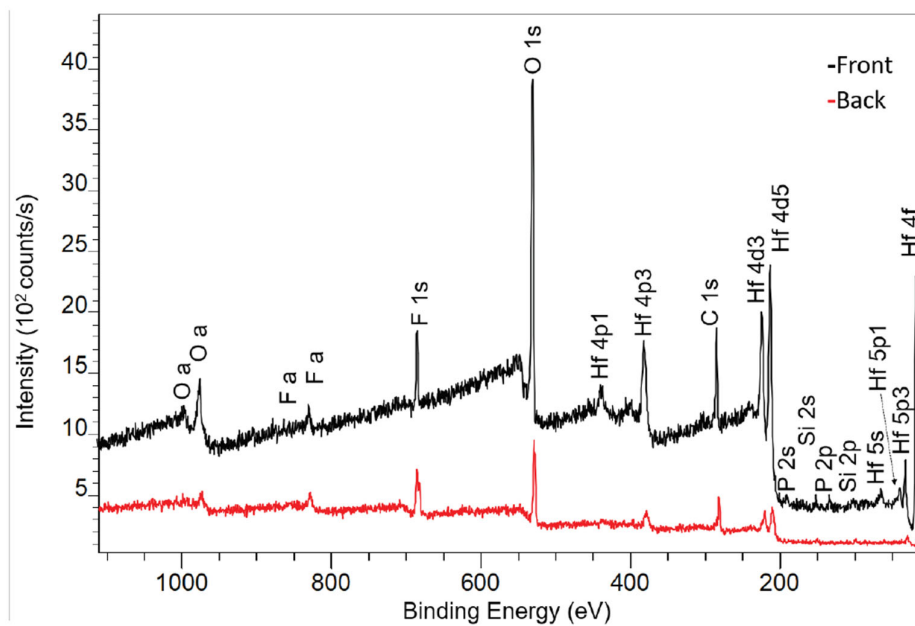
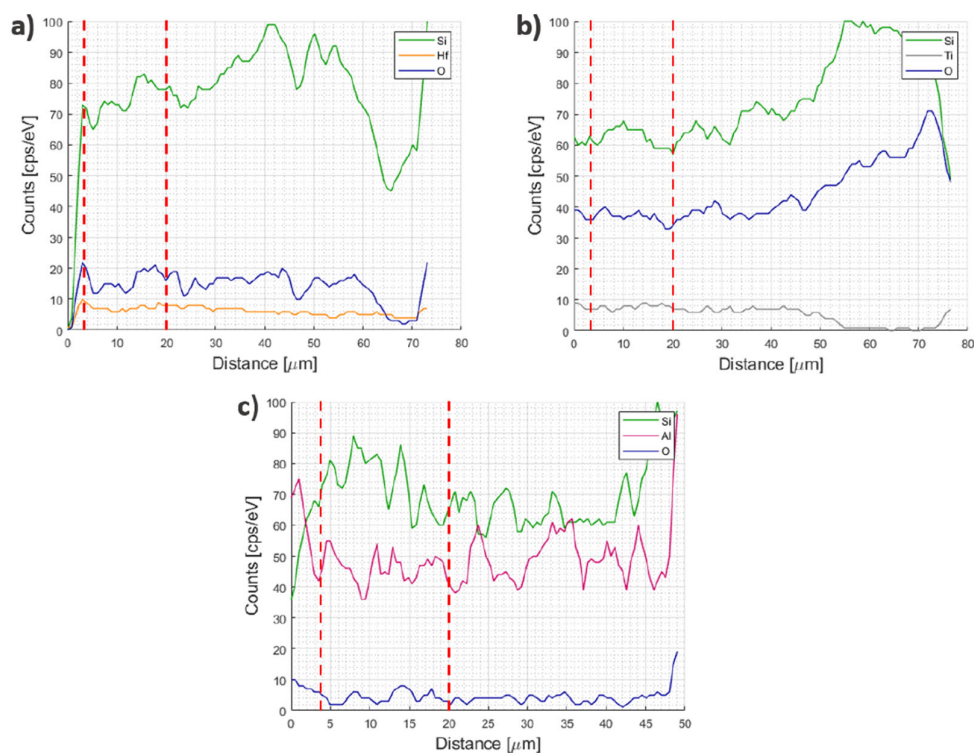


Figure S3. Interferometric spectra obtained for (a) PSiO₂/HfO₂, (b) PSiO₂/TiO₂, and (c) PSiO₂/Al₂O₃, before and after the ALD, at same integration time ($t = 1$ s).



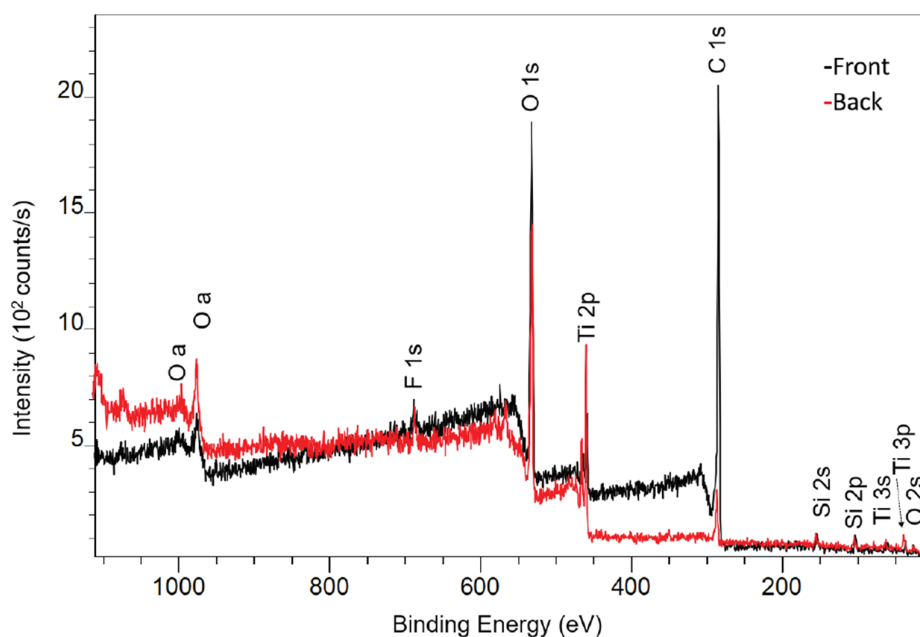


Figure S6. XPS survey spectra of the PSiO₂/TiO₂ membrane front (black) and back (red). The main core levels are labeled. The data are normalized to each C-(C,H) component of the C 1s peak and separated vertically.

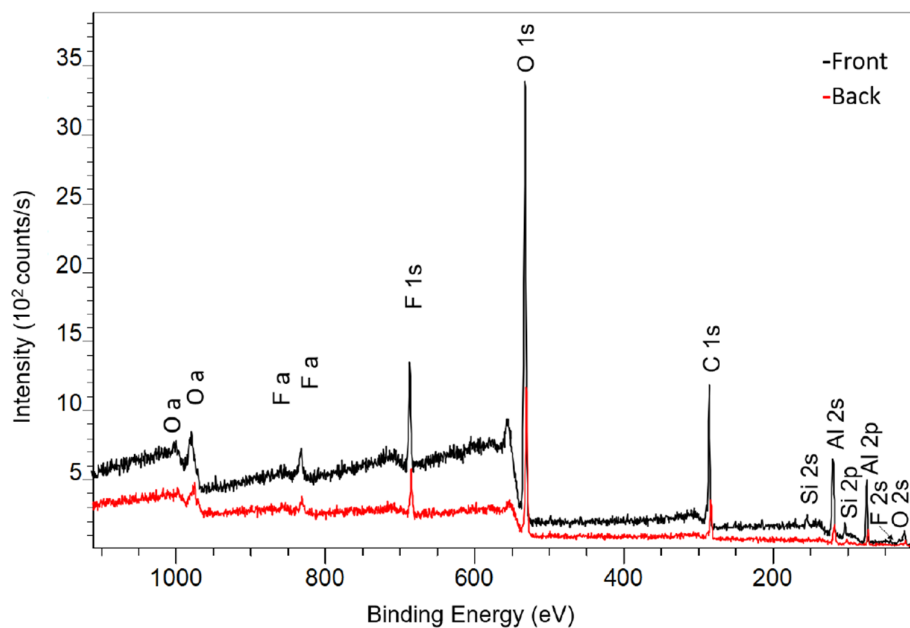


Figure S7. XPS survey spectra of the PSiO₂/Al₂O₃ membrane front (black) and back (red). The main core levels are labeled. The data are normalized to each C-(C,H) component of the C 1s peak and separated vertically.